



Product Change Notification: CENO-19LKKL699

Date:

07-Mar-2025

Product Category:

Power Management - PMIC, Power Management - PWM Controllers, Switching Regulators

Notification Subject:

CCB 6619 Final Notice: Qualification of UNIG as new assembly site for selected MIC2111xx, MIC2225, MIC2285A, MIC23150, MIC232xx, MIC2800, MIC28xx and MIC2821 device families available in various packages.

Affected CPNs:

[CENO-19LKKL699_Affected_CPN_03072025.pdf](#)

[CENO-19LKKL699_Affected_CPN_03072025.csv](#)

PCN Status: Final Notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the files found in the Affected CPNs section.

Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change: Qualification of UNIG as new assembly site for selected MIC2111xx, MIC2225, MIC2285A, MIC23150, MIC232xx, MIC2800, MIC28xx and MIC2821 device families available in various packages.

Pre and Post Summary Changes:

	Pre Change	Post Change
Assembly Site	Unisem (M) Berhad Perak, Malaysia (UNIS)	Unisem Gopeng (UNIG)

Method to Identify Change: Traceability Code

Qualification Report: Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History: November 23, 2023: Issued initial notification.

March 07, 2025: Issued final notification. Attached Qualification Report. Revised affected parts list to remove MIC2111BYMT-T5 and MIC2111CYMT-T5 catalog part numbers due to EOL. Provided Estimated First Ship Date on April 16, 2025.

Note: The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable product.

Attachments:

PCN_CENO-19LKKL699_Qual Report.pdf

Please contact your local **Microchip sales office** with questions or concerns regarding this notification.

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Affected Catalog Part Numbers (CPN)

MIC2810-44MYML-TR
MIC2811-4GMSYML-TR
MIC2810-4MSYML-TR
MIC2225-4OYMT-TR
MIC2225-GJYMT-TR
MIC2800-G4SYML-TR
MIC2810-4GMYML-TR
MIC2821-4GJLYML-TR
MIC2225-4SYMT-TR
MIC2810-1J6JYML-TR
MIC2810-1J6SYML-TR
MIC2800-G1JJYML-TR
MIC2800-G1JSYML-TR
MIC2800-G2SYML-TR
MIC2800-G8SYML-TR
MIC2800-G1JJYML-TR1
MIC23150-SYMT-TR
MIC2800-G4JYML-TR
MIC2800-A4SYML-TR
MIC2811-4GJLYML-TR
MIC2821-4GMSYML-TR
MIC23150-55YMT-TR
MIC23250-S4YMT-TR
MIC23250-SKYMT-TR
MIC23150-GYMT-TR
MIC23250-G4YMT-TR
MIC23250-M4YMT-TR
MIC2225-G4YMT-TR

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MIC2225-GMYMT-TR

MIC2810-4GSYML-TR

MIC2111CYMT-TR

MIC2800-G4MYML-TR

MIC2800-GFMYML-TR

MIC2810-4GPYML-TR

MIC23250-F4YMT-TR

MIC2225-4KYMT-TR

MIC2225-GFYMT-TR

MIC2285AYMT-TR

MIC2800-D2FMYML-TR

MIC23250-W4YMT-TR

MIC2810-4LSYML-TR

MIC2810-FGSYML-TR

MIC2225-4MYMT-TR

MIC23150-4YMT-TR

MIC23150-CYMT-TR

MIC23254-GCYMT-TR

MIC2800-G7SYML-TR

MIC2810-1JGMYML-TR

MIC2800-GFSYML-TR

MIC2111BYMT-TR

MIC2800-G4KYML-TR

MIC2810-4GKYML-TR

MIC2810-CGJYML-TR

MIC2800-D24MYML-TR



QUALIFICATION REPORT SUMMARY

PCN #: CENO-19LKKL699

Date:

February 11, 2025

**Qualification of UNIG as new assembly site for selected
MIC2111xx, MIC2225, MIC2285A, MIC23150, MIC232xx, MIC2800,
MIC28xx and MIC2821 device families available in various
packages.**

Purpose: Qualification of UNIG as new assembly site for selected MIC2111xx, MIC2225, MIC2285A, MIC23150, MIC232xx, MIC2800, MIC28xx and MIC2821 device families available in various packages.

I. Summary:

The purpose of this qualification is to evaluate Reliability performance COL (Chip on lead) package at Unisem Gopeng per CCB 6619, following guidelines established in Microchip specification QCI-39000, "Worldwide Quality Conformance Requirements".

Conclusion:

Based on successful Reliability stress results on test device MIC2800-G1JJYML-TR assembled in 16-lead VQFN, COL (Chip on lead) package at Unisem Gopeng is qualified for production as per guidelines established in Microchip specification QCI-39000, "Worldwide Quality Conformance Requirements".

II. Device Description:

Device	MIC2800-G1JJYML-TR
Product	Digital Power Management 2 MHz, 600 mA DC/DC with Dual Low VIN LDOs
Document Control Number	ML0220257329
Document Revision	A
CCB No.	6619

III. Package Qualification Material:

Test Lot	Lot 1	Lot 2	Lot 3
WAFER LOT	TMPE224275707.110	TMPE224275707.110	TMPE224275707.110
ASSEMBLY LOT	UNIG252400001.000	UNIG252400002.000	UNIG252400003.000.000
PACKAGE	VQFN-16L 3x3x0.90mm	VQFN-16L 3x3x0.90mm	VQFN-16L 3x3x0.90mm
QUAL TESTS	HTSL, HAST, UHAST, TC	HTSL, HAST, UHAST, TC	HTSL, HAST, UHAST, TC

IV. Package BOM

<u>Misc.</u>	Assembly site	UNIG
	BD Number	A-062015
	MP Code (MPC)	22837YN8AA21
	Part Number (CPN)	MIC2800-G1JJYML-TR
	MSL information	MSL 2, 260°C
	Assembly Shipping Media (T/R, Tube/Tray)	T&R
	Base Quantity Multiple (BQM)	5000
	Reliability Site	UNIS, SJ
<u>Lead-Frame</u>	Paddle size	85x85mils
	Material	A194FH
	DAP Surface Prep	NiPdAu
	Treatment	No
	Process	Etch
	Lead-lock	Yes
	Part Number	40000469
	Lead Plating	NiPdAu
	Strip Size	70x250mm
	Strip Density	960
<u>Bond Wire</u>	Material	Au
<u>Die</u>	Part Number	8006NS
	Conductive	No
<u>MC</u>	Part Number	G770HCD
<u>PKG</u>	Package Type	VQFN
	Pin/Ball Count	16
	PKG width/size	3x3x0.90mm

V. Qualification Data:

Package Preconditioning:

Test Method/Condition	JEDEC J-STD-020 and JESD22-A113, MSL Level 2 soak at +85°C/60%RH/168hrs, 3x at 260°C peak Reflow Temperature
Lot #	ATE Test Results (Fail/Sample Size)
Lot 1	0/246,
Lot 2	0/246,
Lot 3	0/255,

Pre and Post testing was conducted at +25°C

HAST Post MSL2 Preconditioning.

Test Method/Condition	JESD22-A110, Vin = +5.5V, Ta = +130°C/85%RH, 96 hrs. Minimum sample size = 77
Lot #	Results (Fail/Sample Size) minimum sample size = 77
Lot 1	0/81
Lot 2	0/82
Lot 3	0/82

Pre and Post testing was conducted at +25°C

Unbiased HAST post MSL2 Precondition.

Test Method/Condition	JESD22-A118, Ta = +130°C/85%RH, 96hrs. Minimum sample size = 77
Lot #	Results (Fail/Sample Size)
Lot 1	0/82
Lot 2	0/82
Lot 3	0/82

Pre and Post testing was conducted at +25

Temperature Cycling post MSL2 Preconditioning

Test Method/Condition	JESD22-A104, Ta = -65°C/+150 °C, 500 cycles. Minimum sample size = 77
Lot #	Results (Fail/Sample Size)
Lot 1	0/82
Lot 2	0/82
Lot 3	0/82

Pre and Post testing was conducted at +25°C

High Temperature Storage Life

Test Method/Condition	JESD22-A103, Ta = +150 °C, 1000 hrs
Lot #	Results (Fail/Sample Size) minimum sample size = 45
Lot 1	0/82
Lot 2	0/82
Lot 3	0/82

Pre and Post testing was conducted at +25°C

